

1x2Mx32bit DRAM Card
2x2Mx32bit DRAM Card

MF18M1-L57ATXX
MF116M-L57ATXX

Connector Type

Two-piece 88-pin

DESCRIPTION

These DRAM CARDS are developed based on JEIDA DRAM CARD GUIDELINE Ver. 2.1. These cards are made using industry standard 2 M × 8 Dynamic RAM and interface IC's in TSOP.

FEATURES

- Operating Voltage : $V_{CC}=5V \pm 5\%$
- All inputs except \overline{RAS} inputs are buffered.
- Standard card size : 54mm (W) × 85.6mm (L) × 3.3mm (T)
- 88pin 2 piece connector type.
- \overline{RAS} only refresh mode, \overline{CAS} before \overline{RAS} refresh mode and Page mode functions are available.
- Extended refresh is available. (128ms/2048cycle)

APPLICATIONS

Main/expansion memory unit for Personal Computer. Laser-Printer, FAX etc.

PRODUCT LIST

Product No.	Item Type name	Memory capacity	Data Bus width (bits)	Access time (t _{TRAC}) (ns)	Connector type	Number of pins	Outline drawing
No. 1	MF18M1-L57ATXX	8 MB	32	70	Two-piece	88	88P-001
No. 2	MF116M-L57ATXX	16MB	(without parity)				

DYNAMIC RAM CARDS

PIN ASSIGNMENT

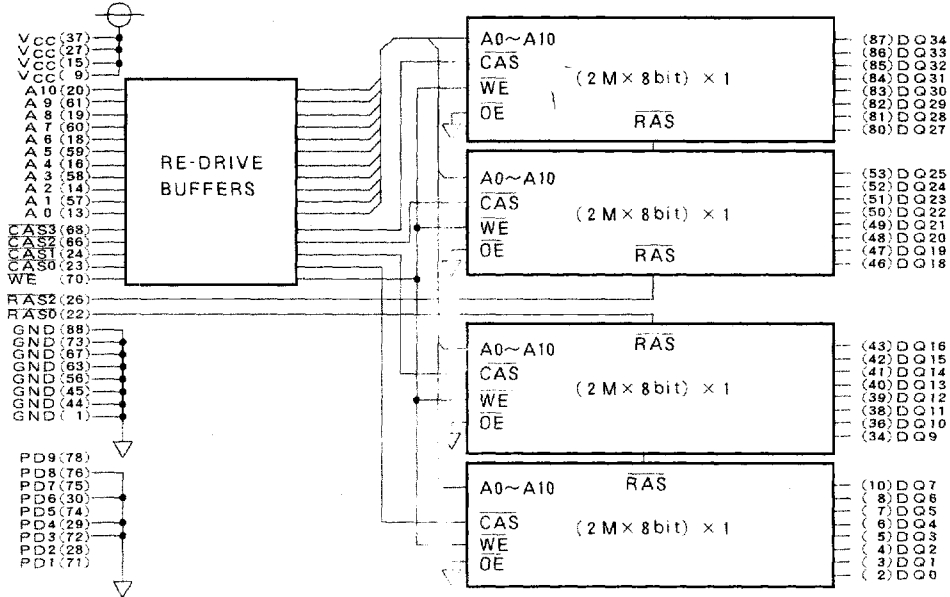
Pin No.	Symbol	Function	Pin No.	Symbol	Function	
1	GND	Ground	45	GND	Ground	
2	DQ 0	Data I/O	46	DQ 18	Data I/O	
3	DQ 1		47	DQ 19		
4	DQ 2		48	DQ 20		
5	DQ 3		49	DQ 21		
6	DQ 4		50	DQ 22		
7	DQ 5		51	DQ 23		
8	DQ 6		52	DQ 24		
9	Vcc		Power supply voltage	53		DQ 25
10	DQ 7	Data I/O	54	NC	No connection	
11	NC	No connection	55	NC	No connection	
12	NC	No connection	56	GND	Ground	
13	A 0	Address input	57	A 1	Address input	
14	A 2		58	A 3		
15	Vcc		Power supply voltage	59		A 5
16	A 4	Address input	60	A 7		
17	NC	No connection	61	A 9		
18	A 6	Address input	62	NC	No connection	
19	A 8		63	GND	Ground	
20	A 10		64	NC	No connection	
21	NC	No connection	65	<u>RAS 1</u>	Row address strobe 1 (NC for No. 1)	
22	<u>RAS 0</u>	Row address strobe 0	66	<u>CAS 2</u>	Column address strobe 2	
23	<u>CAS 0</u>	Column address strobe 0	67	GND	Ground	
24	<u>CAS 1</u>	Column address strobe 1	68	<u>CAS 3</u>	Column address strobe 3	
25	NC	No connection	69	<u>RAS 3</u>	Row address strobe 3 (NC for No. 1)	
26	<u>RAS 2</u>	Row address strobe 2	70	<u>WE</u>	Write enable	
27	Vcc	Power supply voltage	71	PD 1	Presence detect 1	
28	PD 2	Presence detect 2	72	PD 3	Presence detect 3	
29	PD 4	Presence detect 4	73	GND	Ground	
30	PD 6	Presence detect 6	74	PD 5	Presence detect 5	
31	NC	No connection	75	PD 7	Presence detect 7	
32	NC		76	PD 8	Presence detect 8	
33	NC	No connection	77	NC	No connection	
34	DQ 9	Data I/O	78	PD 9	Presence detect 9	
35	NC	No connection	79	NC	No connection	
36	DQ 10	Data I/O	80	DQ 27	Data I/O	
37	Vcc	Power supply voltage	81	DQ 28		
38	DQ 11	Data I/O	82	DQ 29		
39	DQ 12		83	DQ 30		
40	DQ 13		84	DQ 31		
41	DQ 14		85	DQ 32		
42	DQ 15		86	DQ 33		
43	DQ 16		87	DQ 34		
44	GND		Ground	88	GND	Ground

PD Pin Table

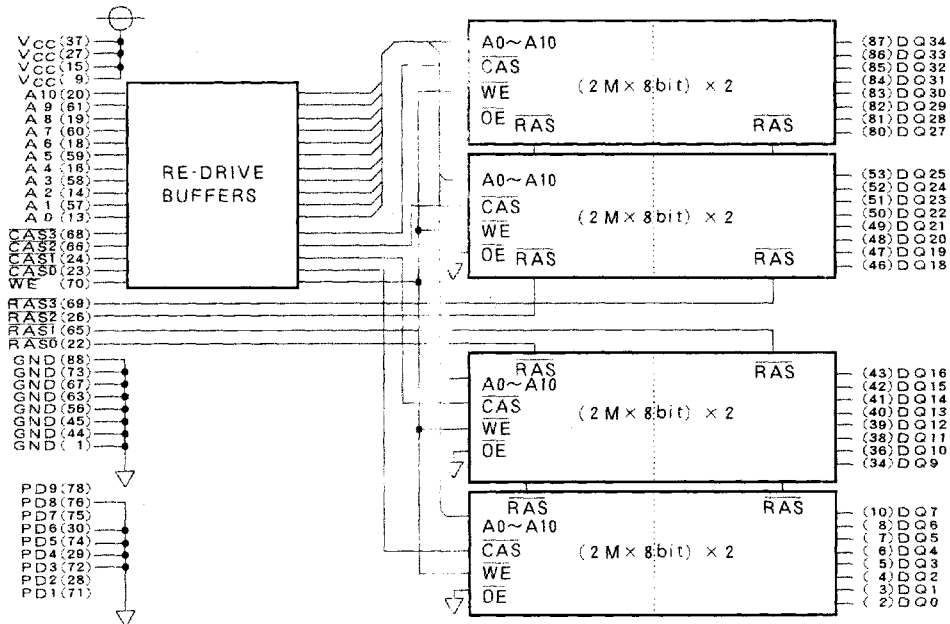
Product No.	PD 1	PD 2	PD 3	PD 4	PD 5	PD 6	PD 7	PD 8	PD 9
No. 1	N. C.	N. C.	GND	GND	NC	GND	NC	GND	N. C.
No. 2	N. C.	N. C.	GND	GND	GND	GND	NC	GND	N. C.

DYNAMIC RAM CARDS

BLOCK DIAGRAM (No.1)



BLOCK DIAGRAM (No.2)



DYNAMIC RAM CARDS

FUNCTION TABLE

Operation	input					input/output		Refresh	Note
	RAS	CAS	WE	Row Address	Column Address	input	output		
Read	ACT	ACT	NAC	APD	APD	OPN	VLD	YES	Page mode identical
Early write	ACT	ACT	ACT	APD	APD	VLD	OPN	YES	
RAS only refresh	ACT	NAC	DNC	APD	DNC	DNC	OPN	YES	
CAS before RAS refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Self refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Standby	NAC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note 1 : ACT : active, NAC : nonactive, DNC : don't care, VLD : valid, APD : applied, OPN : open
 Don't be active the even and odd No. RASs at the same time. (Read/Early write cycle only)

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings		Unit
			No. 1	No. 2	
V _{CC}	Supply voltage	With respect to GND	-0.5~7		V
V _I	Input voltage		-0.5~V _{CC} +0.5(7V max)		V
V _O	Output voltage		-0.5~7		V
I _O	Output current		50		mA
P _d	Power dissipation	T _a = 25°C	4	8	W
T _{opr}	Operating temperature		0~55		°C
T _{stg}	Storage temperature		-40~80		°C

RECOMMENDED OPERATING CONDITIONS (T_a = 0~55°C, unless otherwise noted): (Note 2)

Symbol	Parameter	Limits			Unit
		Min.	Typ.	Max.	
V _{CC}	Supply voltage	4.75	5	5.25	V
GND	Supply voltage	0	0	0	V
V _{IH}	High input voltage	0.7 × V _{CC}		V _{CC}	V
V _{IL}	Low input voltage	0		0.8	V

Note 2 : With respect to GND

DYNAMIC RAM CARDS

ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 55^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, $GND = 0\text{V}$): (Note 3)

Symbol	Parameter	Test condition	Limits					Unit
			Min.		Typ.	Max.		
			No.1	No.2		No.1	No.2	
V_{OH}	High output voltage	$I_{OH} = -5\text{mA}$	2.4			V_{CC}		V
V_{OL}	Low output voltage	$I_{OL} = 4.2\text{mA}$	0			0.4		V
I_{OZ}	Off-stage output current	$0\text{V} \leq V_{OUT} \leq V_{CC}$	-10	-20		10	20	μA
I_I	Input current	$0\text{V} \leq V_{IN} \leq V_{CC}$ Other input pins = 0 V	-20	-20		20	20	μA
$I_{CC1(AV)}$	Average supply current from V_{CC} , operating (Note 4, 5, 6)	\overline{RAS} , \overline{CAS} cycling $t_{RC} = t_{WC} = \text{min}$, output open				460	480	mA
$I_{CC2(AV)}$	Supply current from V_{CC} , standby (Note 7)	$\overline{RAS} = \overline{CAS} \geq V_{CC} - 0.2\text{V}$, other input pins $\geq V_{CC} - 0.2\text{V}$ or $\leq 0.2\text{V}$, output open				5.0	9.0	mA
$I_{CC3(AV)}$	Average supply current from V_{CC} , refreshing (Note 4, 6)	\overline{RAS} cycling, $\overline{CAS} = V_{IH}$ $t_{RC} = \text{min}$, output open				510	1000	mA
$I_{CC4(AV)}$	Average supply current from V_{CC} , Page-Mode (Note 4, 5, 6)	$\overline{RAS} = V_{IL}$, \overline{CAS} cycling $t_{RC} = \text{min}$, output open				360	390	mA
$I_{CC6(AV)}$	Average supply current from V_{CC} , \overline{CAS} before \overline{RAS} refresh mode (Note 4, 6)	\overline{CAS} before \overline{RAS} refresh cycling $t_{RC} = \text{min}$, output open				490	970	mA
$I_{CC8(AV)}$	Average supply current from V_{CC} , Extended refresh mode (Note 7)	\overline{CAS} before \overline{RAS} refresh cycling $\overline{WE} \geq V_{CC} - 0.2\text{V}$ other input pins $\geq V_{CC} - 0.2\text{V}$ or $\leq 0.2\text{V}$, output open $t_{RC} = 62.5\mu\text{s}$ ($t_{RAS} = t_{RAS\text{min}} \sim 1\mu\text{s}$)				11	14	mA
$I_{CC9(AV)}$	Average supply current from V_{CC} , Self refresh mode (Note 7)	$\overline{RAS} = \overline{CAS} \leq 0.2\text{V}$, $\overline{WE} \geq V_{CC} - 0.2\text{V}$ output open				11	14	mA

Note 3 : Current flowing into a CARD is positive, out is negative.

4 : $I_{CC1(AV)}$, $I_{CC3(AV)}$, $I_{CC4(AV)}$ and $I_{CC6(AV)}$ are dependent on cycle rate.

Specified values are obtained at the fastest cycle rate.

5 : $I_{CC1(AV)}$ and $I_{CC4(AV)}$ are dependent on output loading.

Specified values are obtained with the outputs open.

6 : Column Address can be changed once or less while $\overline{RAS} = V_{IL}$ and $\overline{CAS} = V_{IH}$.

DYNAMIC RAM CARDS

SWITCHING CHARACTERISTICS ($T_a = 0 \sim 55^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, $GND = 0\text{V}$): (Note 7)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tCAC	Access time from $\overline{\text{CAS}}$ (Note 8, 9)		27	ns
tRAC	Access time from $\overline{\text{RAS}}$ (Note 8, 10)		70	ns
tCAA	Column Address access time (Note 8, 11)		42	ns
tOFF	Output disable time after $\overline{\text{CAS}}$ high (Note 12)	0	27	ns

Note 7 : An initial pause of 500 μsec is required after power-up followed by any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles before proper device operation is achieved. Note that $\overline{\text{RAS}}$ may be cycled during the initial pause. And any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles are required after prolonged periods of $\overline{\text{RAS}}$ inactivity before proper device operation is achieved.

8 : Measured with a load circuit equivalent to 2 TTL loads and 100pF.

9 : Assume that $t_{\text{RCD}} \geq t_{\text{RCD(max)}}$ and $t_{\text{ASC}} \geq t_{\text{ASC(max)}}$.

10 : Assume that $t_{\text{RCD}} \geq t_{\text{RCD(max)}}$ and $t_{\text{RAD}} \leq t_{\text{RAD(max)}}$.

11 : Assume that $t_{\text{RAD}} \geq t_{\text{RAD(max)}}$ and $t_{\text{ASC}} \leq t_{\text{ASC(max)}}$.

12 : $t_{\text{OFF(max)}}$ define the time at which the output achieves the high impedance state (No.1 : $|I_{\text{OUT}}| \leq 10\ \mu\text{A}$, No.2 : $|I_{\text{OUT}}| \leq 20\ \mu\text{A}$) and are not reference to $V_{\text{OH(min)}}$ or $V_{\text{OL(max)}}$.

TIMING REQUIREMENTS ($T_a = 0 \sim 55^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, $GND = 0\text{V}$): (Note 13, 14)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tREF	Refresh cycle time		32	ms
tREF	Refresh cycle time (CAS before $\overline{\text{RAS}}$ refresh cycling)		128	ms
tRP	$\overline{\text{RAS}}$ high pulse width	50		ns
tRCD	Delay time, $\overline{\text{RAS}}$ low to $\overline{\text{CAS}}$ low (Note 15)	20	43	ns
tCRP	Delay time, $\overline{\text{CAS}}$ high to $\overline{\text{RAS}}$ low (Note 16)	17		ns
tRPC	Precharge to $\overline{\text{CAS}}$ active time.	0		ns
tCPN	$\overline{\text{CAS}}$ high pulse width	10		ns
tRAD	Column address delay time from $\overline{\text{RAS}}$ low (Note 17)	17	28	ns
tASR	Row address setup time before $\overline{\text{RAS}}$ low	10		ns
tASC	Column address setup time before $\overline{\text{CAS}}$ low (Note 18)	5	10	ns
tRAH	Row address hold time after $\overline{\text{RAS}}$ low	10		ns
tCAH	Column address hold time after $\overline{\text{CAS}}$ low	15		ns
tT	Transition time (Note 19)	3	50	ns

Note 13 : The timing requirements are assumed $t_T = 5\text{ns}$.

14 : $V_{\text{IH(min)}}$ and $V_{\text{IL(max)}}$ are reference levels for measuring timing of input signals.

15 : $t_{\text{RCD(max)}}$ is specified as a reference point only.

If $t_{\text{RCD}} \geq t_{\text{RCD(max)}}$, access time is defined as tCAC and tCAA.

16 : tCRP requirement is applicable for all $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles.

17 : $t_{\text{RAD(max)}}$ is specified as a reference point only.

If $t_{\text{RAD}} \geq t_{\text{RAD(max)}}$ and $t_{\text{ASC}} \leq t_{\text{ASC(max)}}$, access time is assumed by tCAA for read cycle.

18 : $t_{\text{ASC(max)}}$ is specified as a reference point only of address access time.

19 : t_T is measured between $V_{\text{IH(min)}}$ and $V_{\text{IL(max)}}$.

DYNAMIC RAM CARDS

Read and Refresh Cycles

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tRC	Read cycle time	130		ns
tRAS	RAS low pulse width	70	10000	ns
tCAS	CAS low pulse width	20	10000	ns
tCSH	CAS hold time after RAS low	70		ns
tRSH	RAS hold time after CAS low	27		ns
tRSC	Read setup time before CAS low	5		ns
tRCH	Read hold time after CAS high	0		ns
tRRH	Read hold time after RAS high	10		ns

Write Cycle (Early Write)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tWC	Write cycle time	130		ns
tRAS	RAS low pulse width	70	10000	ns
tCAS	CAS low pulse width	20	10000	ns
tCSH	CAS hold time after RAS low	70		ns
tRSH	RAS hold time after CAS low	27		ns
tWCS	Write setup time before CAS low	5		ns
tWCH	Write hold time after CAS low	15		ns
tDS	Data setup time	19		ns
tDH	Data hold time after CAS low	22		ns

Page Mode Cycle (Read, Early Write)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tPC	Read, Write cycle time	55		ns
tCP	CAS high pulse width	10		ns
tRAS	RAS low pulse width (Note 20)	125	100000	ns

Note 20 : tRAS(min) is specified by the following formula as two cycles of CAS input are executed.
 $tRAS(min) = tCSH(min) + tPC(min)$.

CAS before RAS Refresh Cycle (Note 21)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tCSR	CAS setup time for CAS before RAS refresh	20		ns
tCHR	CAS hold time for CAS before RAS refresh	15		ns

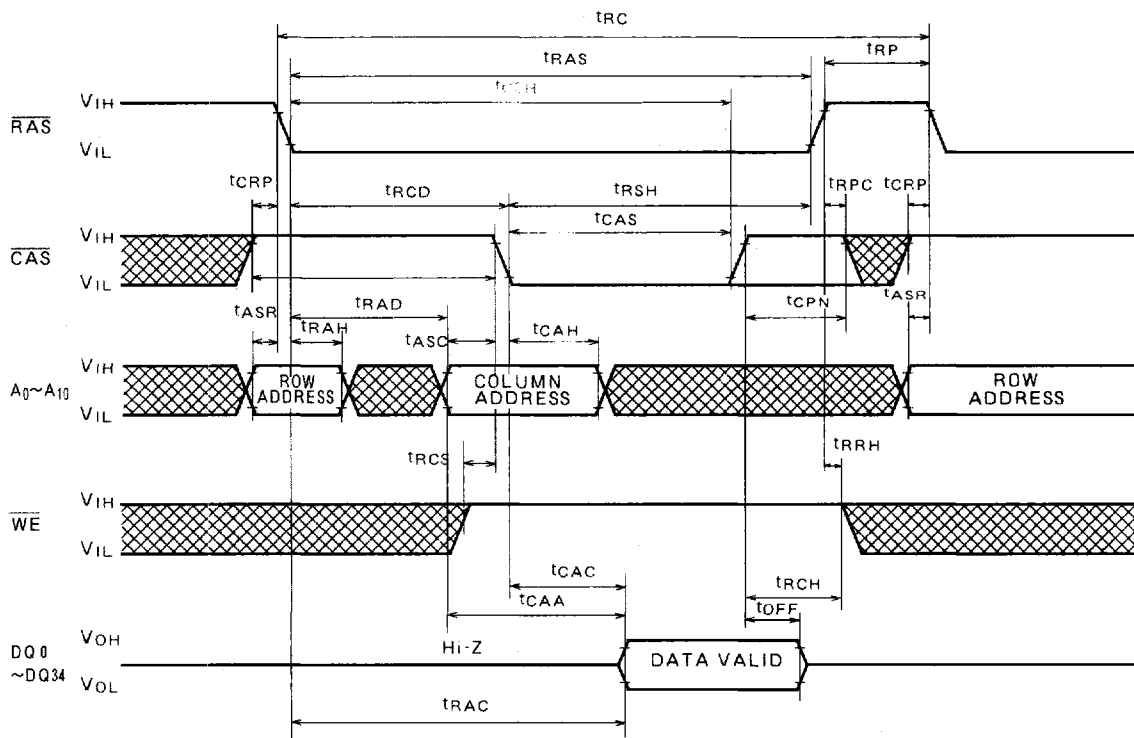
Note 21 : Eight or more CAS before RAS cycles are necessary for proper operation of CAS before RAS refresh mode.

Self Refresh Cycle

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tRASS	RAS low pulse width	100		μs
tRPS	CAS high pulse width	130		ns
tCHS	RAS hold time after RAS high	-50		ns

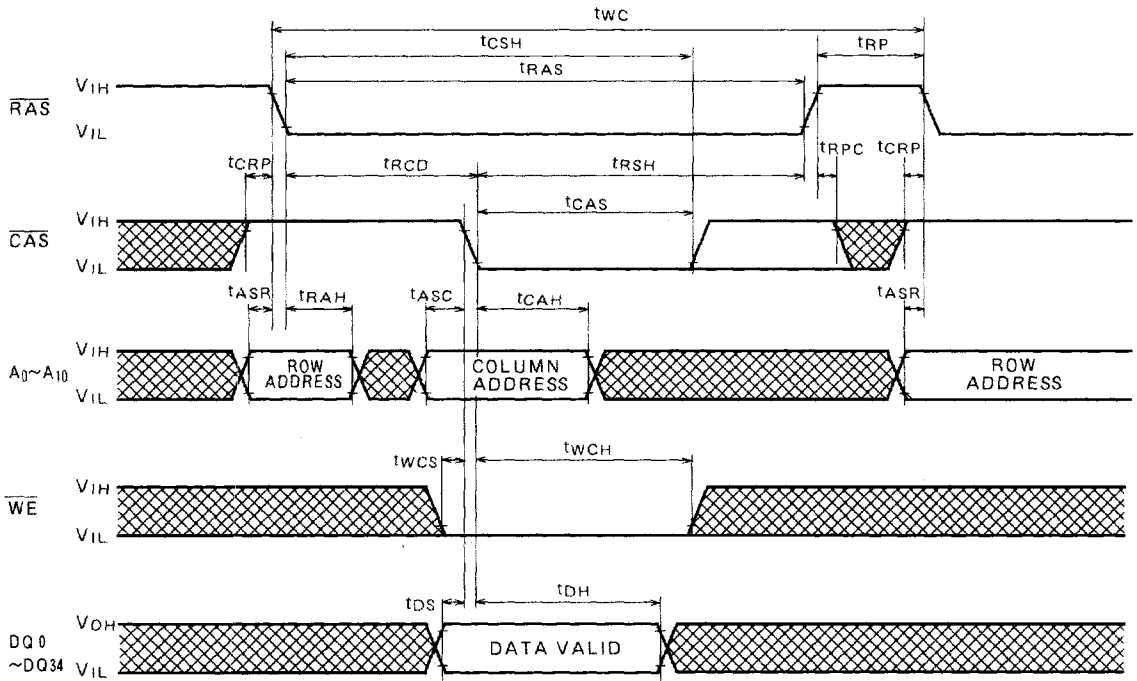
TIMING DIAGRAMS (Note 22)

Read Cycle

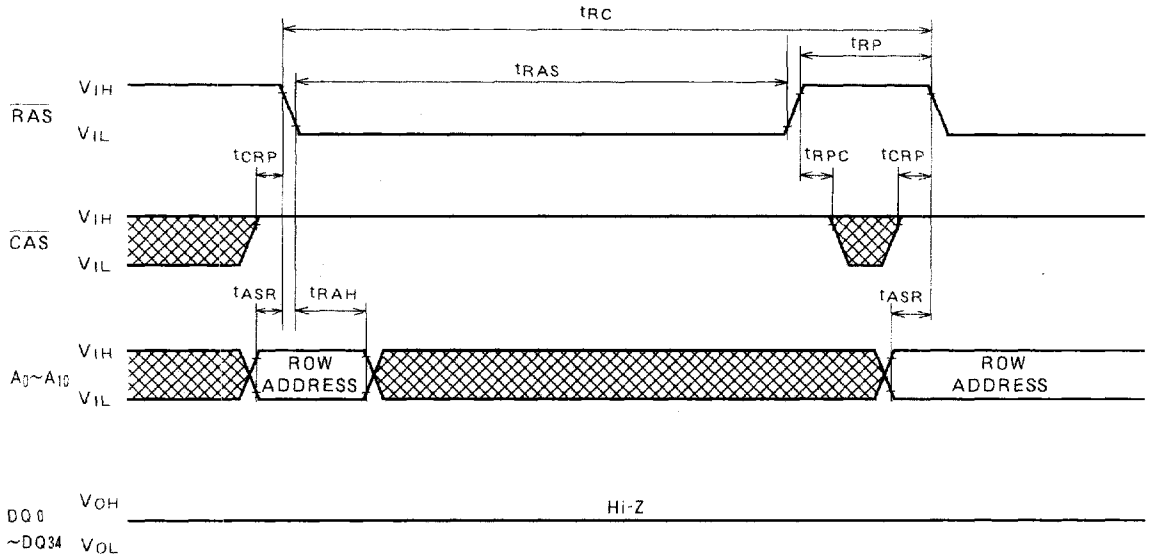


Note 22 :  Indicates the don't care input.

Early Write Cycle

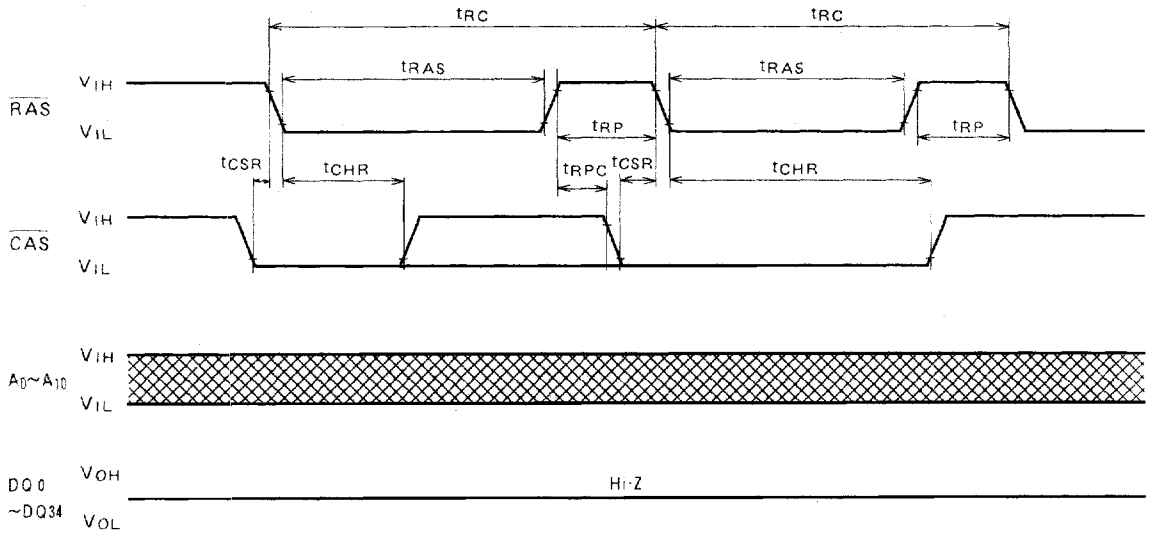


RAS only Refresh Cycle (Note 23)



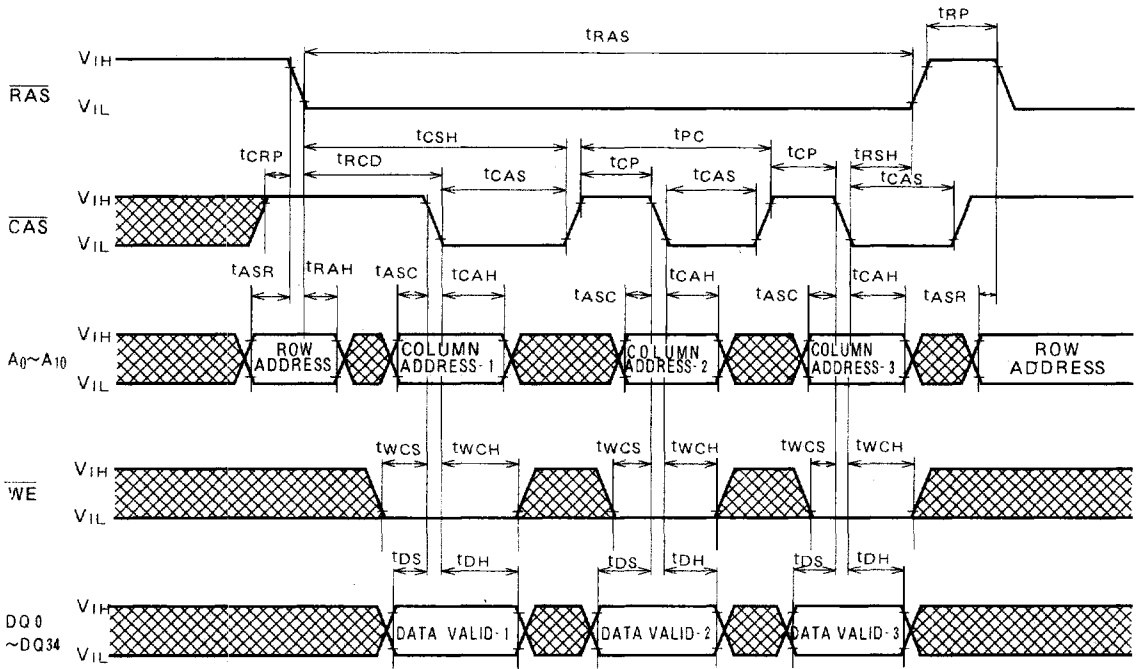
Note 23 : $\overline{\text{WE}}$ = don't care.

CAS before RAS Refresh Cycle (Note 24)



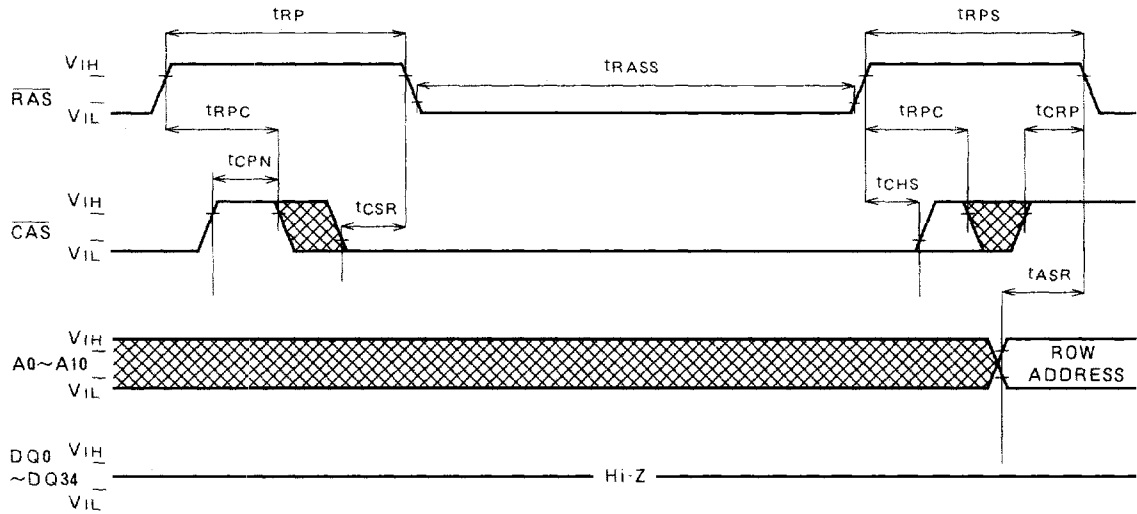
Note 24 : $\overline{\text{WE}}$ = V_{IH}

Page-Mode Early Write Cycle



DYNAMIC RAM CARDS

Self Refresh Cycle (Note 25, 26)

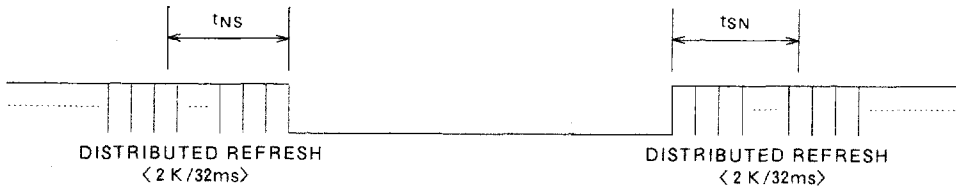


Note 25 : $\overline{WE} = V_{IH}$

Note 26 : SELF REFRESH ENTRY & EXIT CONDITIONS

(1) In case of distributed refresh

The last/first full refresh cycles (2 K) must be made within t_{NS}/t_{SN} before/after self refresh, on the condition of $t_{NS} \leq 32\text{ms}$ and $t_{SN} \leq 32\text{ms}$.



(2) In case of burst refresh

The last/first full refresh cycles (2 K) must be made within t_{NS}/t_{SN} before/after self refresh, on the condition of $t_{NS} + t_{SN} \leq 32\text{ms}$.

